

Special Issue

Single-Pixel Intelligent Imaging and Recognition

Message from the Guest Editor

This Special Issue focuses on the development and application of single-pixel imaging and ghost imaging technology. Single-pixel imaging, a type of computational imaging, originated from ghost imaging technology and achieves imaging through structured light illumination and the collection of light intensity information using a single-pixel detector. Ghost imaging underwent a development process from quantum ghost imaging to classical ghost imaging and then to computational ghost imaging. Combining deep learning algorithms for single-pixel imaging and moving object recognition has significant application advantages, especially in special bands such as infrared and terahertz bands. We welcome manuscripts involving theoretical and experimental research in related fields.

Guest Editor

Prof. Lu Gao

School of Science, China University of Geosciences, Beijing 100083, China

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Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
appls@mdpi.com

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Message from the Editor-in-Chief

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Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,
20133 Milano, Italy

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